

<b>Notice of References Cited</b>		Application/Control No. 10/598,090	Applicant(s)/Patent Under Reexamination NOHNO ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0028393 A1	10-2001	Tomida et al.	348/207
*	B	US-2003/0137586 A1	07-2003	Lewellen, Mark A.	348/148
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003-16595 (Trans.)	01-2003	Japan	Makoto	G08G 1/16
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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